

BUNCH DIFFUSION MEASUREMENTS AT THE ADVANCED LIGHT SOURCE*

W. E. Byrne, C-W. Chiu, J-H. Guo, F. Sannibale, LBNL, Berkeley, CA 94720, U.S.A.
J.S. Hull, O.H.W. Siegmund, A. S. Tremsin, J.V. Vallergera UCB-SSL, Berkeley, CA 94720, U.S.A.

Abstract

In storage ring based synchrotron light sources, a long beam lifetime is usually a fundamental requirement for a high integrated brightness. The dynamic aperture and the momentum acceptance of lattices are carefully studied and maximized as much as possible for a long lifetime performance. On the other hand, large momentum acceptance and dynamic aperture increase the probability that a particle diffuses from one bunch to another. Diffusion can represent a severe limitation for those experiments where the samples have long relaxation times requiring empty buckets between bunches. At the Advanced Light Source (ALS) of the Lawrence Berkeley National Laboratory we have characterized the particle diffusion for the present lattice in order to evaluate its impact on a special user operation dedicated to these long relaxation time experiments and on the incoming top-off injection mode for the ALS.

INTRODUCTION

The Advanced Light Source (ALS) at the Lawrence Berkeley National Laboratory is a third generation synchrotron light source operating at 1.9 GeV and optimized for the generation of high brightness soft x-rays. Twice per year a special user operation shift of two weeks is dedicated to experiments where a long relaxation time for the samples is required. During such a period, only two opposite bunches are stored in the ring with about 30 mA of current each. Experiments require that all the other 326 remaining buckets must be free from particles at a "purity" level of $\sim 0.001\%$ of the total stored current. Such a requirement can only be fulfilled by using special procedures that clean the "empty" buckets of undesired particles, which can be due to non-perfect injection, for example. Even after a successful cleaning, particle diffusion from one bunch to another can progressively repopulate empty buckets, necessitating a new cleaning procedure after some period of time. Because of this, characterization of the diffusion rate is important so the proper bunch cleaning strategy can be adopted.

The diffusion rate depends on the ring lattice and in particular on its dynamic aperture and momentum acceptance. In modern storage rings, these two parameters are usually carefully maximized for a long beam lifetime. In this situation, longitudinal phase space trajectories outside the RF bucket can exist and can bring a beam particle scattered by synchrotron radiation emission, Coulomb scattering, residual gas scattering, etc., from the

parent bunch to the proximity of a following bucket. At this point, a new photon emission or a scattering phenomenon can result in the "capture" of the particle by the bucket, generating diffusion.

In this paper the diffusion measurements performed with the present ALS lattice are presented.

BUNCH POPULATION MONITOR DESCRIPTION

The bunch population at the ALS was measured with a photon counting detector at beamline BL 7.0.1, in the branch dedicated to x-ray inelastic scattering experiments. Figure 1 shows a schematic diagram of the beamline. Samples of different materials can be illuminated by a pulsed monochromatic x-ray beam. The timing and duration of each photon bunch is determined by the position and length of electron bunches in the storage ring and the brightness of the photon bunch is proportional to the number of electrons in the electron bunch.

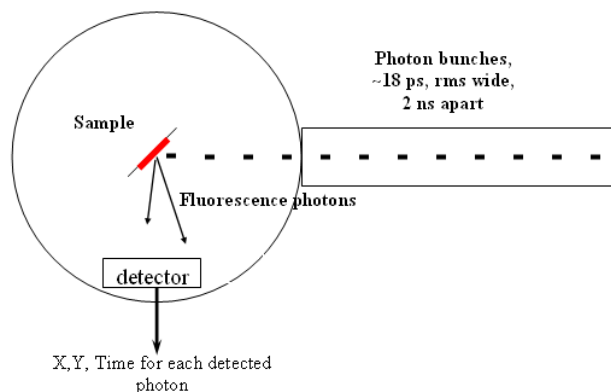


Fig. 1. Schematic diagram of the experimental set-up on BL 7.0.1. The X-ray photons from the pulsed source excite the sample, which fluoresces under X-ray irradiation. A position sensitive photon counting detector records individual fluorescence photons. The time of each photon is measured relative to the orbit clock signal. Different materials have been investigated, some of which do not result in any delay in the emitted fluorescence photon.

The ability of BL 7.0.1 to accurately measure the timing of each recorded photon allowed us to investigate the brightness and timing of the photon bunches which are, in turn, directly related to the longitudinal distribution and number of electrons in the storage ring bunches. The intensity of the scattered photon beam is tuned in order to

* Work supported by the Director, Office of Science, of the U.S. Department of Energy under Contract DE-AC02-05CH11231.

DATA ANALYSIS

Let us consider two contiguous bunches. The first one, which we will indicate as the main bunch, contains several orders of magnitude more particles than the second one, referred as the parasite bunch. The rate of change in the number of particles in the parasite bunch is given by:

$$\frac{dN_D}{dt} = DN_M(t) - \frac{N_D(t)}{\tau_D} \quad (1)$$

where N_D and N_M are the number of particles in the parasite and main bunches respectively, τ_D is the parasite bunch lifetime and D is the diffusion coefficient. D is a constant that represents the probability that a particle diffuses from the main bunch to the parasite one in a unit of time.

The population in the main bunch at a given instant is given by:

$$N_M(t) = N_{M0} \exp(-t/\tau_M) \quad (2)$$

where τ_M is the main bunch lifetime and N_{M0} its population for $t = 0$.

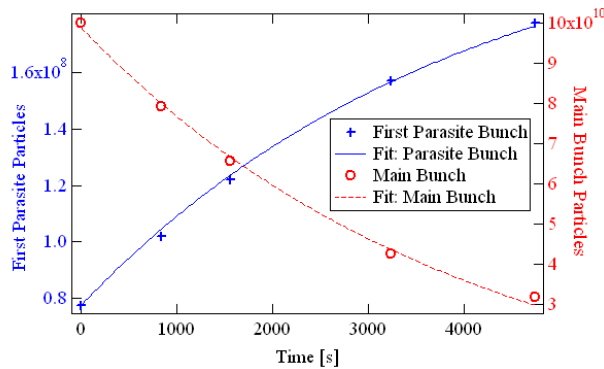


Figure 4. Crosses and circles: measured number of particles in the main and in the parasite bunches as a function of time. Solid and dashed curves: theory fitting functions.

The second term in the right hand side of Eqn. (1) becomes negligible when:

$$D \gg \frac{N_D}{N_M} \frac{1}{\tau_D} \quad (3)$$

In the following derivation, we assume that condition (3) is fulfilled and so we neglect this term. The validity of such an assumption will be verified once the value for D

is known. Neglecting the term in Eqn. (1) and using Eqn. (2) we can integrate with respect to time, obtaining the following expression for the population of the parasite bunch:

$$N_D(t) = N_{D0} + \tau_M DN_{M0} [1 - \exp(-t/\tau_M)] \quad (4)$$

The values $N_{D0} \sim 7.7 \times 10^7$ and $N_{M0} \sim 9.9 \times 10^{10}$ were extracted from the data in Fig. 4. Equation (2) was used for fitting the main bunch data (red dashed curve in Fig. 4) obtaining a value for τ_M during the measurement of ~ 3960 s. This lifetime and Eqn. (4) were then used for fitting the parasite bunch data (blue solid line in Fig. 4), obtaining for the diffusion coefficient:

$$D \cong 3.6 \times 10^{-7} \text{ s}^{-1} \quad (5)$$

Using this value for D and considering that during these measurements τ_D was ~ 40 hours and N_D/N_M was between 10^{-2} and 10^{-3} , one can verify that criterion (3) was actually satisfied.

CONCLUSIONS

The measured diffusion coefficient at the ALS implies that for maintaining the bunch purity of 10^{-5} required by user experiments, a bunch cleaning procedure needs to be performed every ~ 27.5 s. Such a number is compatible with the incoming top-off injection mode of operation where a single shot injection cycle will be performed in the storage ring every ~ 30 s. The new bunch cleaning procedure being used at the ALS [1] generates a small perturbation on the beam that lasts for less than a second. By doing the cleaning right after the injection, the same “veto” signal sent to “sensitive” users to indicate that the beam is being perturbed by the injection transient can also be exploited to alert them of the perturbation from cleaning.

If other modes of operation will require a longer period between two bunch cleaning procedures, then the diffusion coefficient needs to be decreased. This can be achieved, for example, by reducing the dynamic aperture of the lattice and finding the proper compromise between lifetime and a reasonable diffusion rate.

ACKNOWLEDGEMENTS

The authors want to express their thankfulness to the ALS operators for their contribution during the measurements.

REFERENCES

- [1] W. C. Barry et al., “Tests of a new bunch cleaning technique for the Advanced Light Source”, this conference.